

<b>Notice of References Cited</b>	Application/Control No. 10/716,307	Applicant(s)/Patent Under Reexamination YERIAN ET AL.	
	Examiner Maria Veronica D. Ewald	Art Unit 1722	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,802,961	09-1998	Hay et al.	99/406
*	B	US-3,741,699	06-1973	Arpajian et al.	425/145
*	C	US-6,380,517	04-2002	Morgan, Allan C.	219/389
*	D	US-3,645,505	02-1972	McLeod et al.	366/160.3
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.